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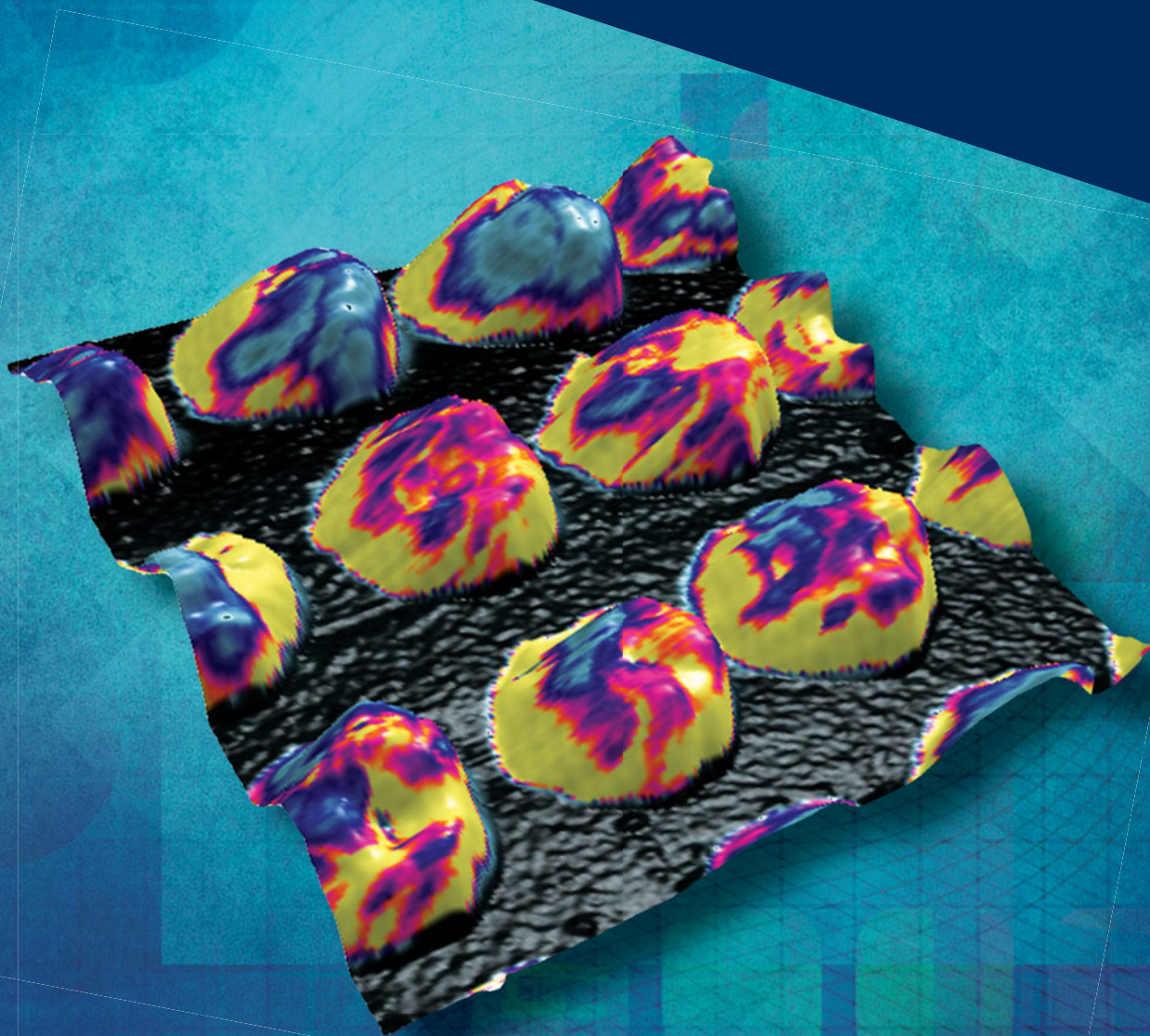


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# Journal of MATERIALS RESEARCH

FOCUS ISSUE

**In-situ and Operando  
Characterization of Materials**



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